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| Notice of References Cited | Application/Control No. 09/997,310 | Applicant(s)/Patent Under Reexamination ZIEGENHORN ET AL. | |
| | Examiner Renata McCloud | Art Unit 2837 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--------------------------------------------------|-----------------|---------------------|----------------|
| | A | US-6,437,291 | 08-2002 | Hopponen, James L. | 219/395 |
| | B | US-5,779,032 | 07-1998 | Iimura et al. | 206/6.1 |
| | C | US-5,371,829 | 12-1994 | Hoeberigs, Henricus | 392/416 |
| | D | US-5,665,438 | 09-1997 | Lee et al. | 428/31 |
| | E | US-6,076,451 | 06-2000 | Studer, Loye E. | 99/340 |
| | F | US-5,970,209 | 10-1999 | Toyokura, Yasuhiro | 392/307 |
| | G | US-5,410,950 | 05-1995 | Rone, Wilbur | 99/421HV |
| | H | US-5,611,264 | 03-1997 | Studer, Loye E. | 99/340 |
| | I | US-5,801,357 | 09-1998 | Danen, Marc | 219/403 |
| | J | US-5,996,572 | 12-1999 | Ilagan, Artemio M. | 126/25AA |
| | K | US-5,058,493 | 10-1991 | Basek et al. | 99/339 |
| | L | US-5,450,841 | 09-1995 | Whitaker et al. | 126/512 |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--------------------------------------------------|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|-------------------------------------------------------------------------------------------|
| | U | |
| | V | |
| | W | |
| | X | |

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